Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/808,497	KIM ET AL.	
Examiner	Art Unit	
Thinh T. Nguyen	2818	

	SEARCHED						
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Class	Subclass	Date	Examiner				
257	315	1/18/2006	TTN				
257	316	1/18/2006	TTN				
257	318	1/18/2006	TTN				

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